Applicant(s)/Patent Under Application/Control No. Reexamination 09/650,218 AVERY ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2131 Shin-Hon Chen **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY 06-1999 Hoehn-Saric et al. US-5,915,973 434/350 US-В US-С US-D US-Ε US-F US-G US-Н US-1 US-J ĸ US-US-L US-**FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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